

Nevis Electronics Test Stand Update

uB DAQ Meeting

January 23, 2013

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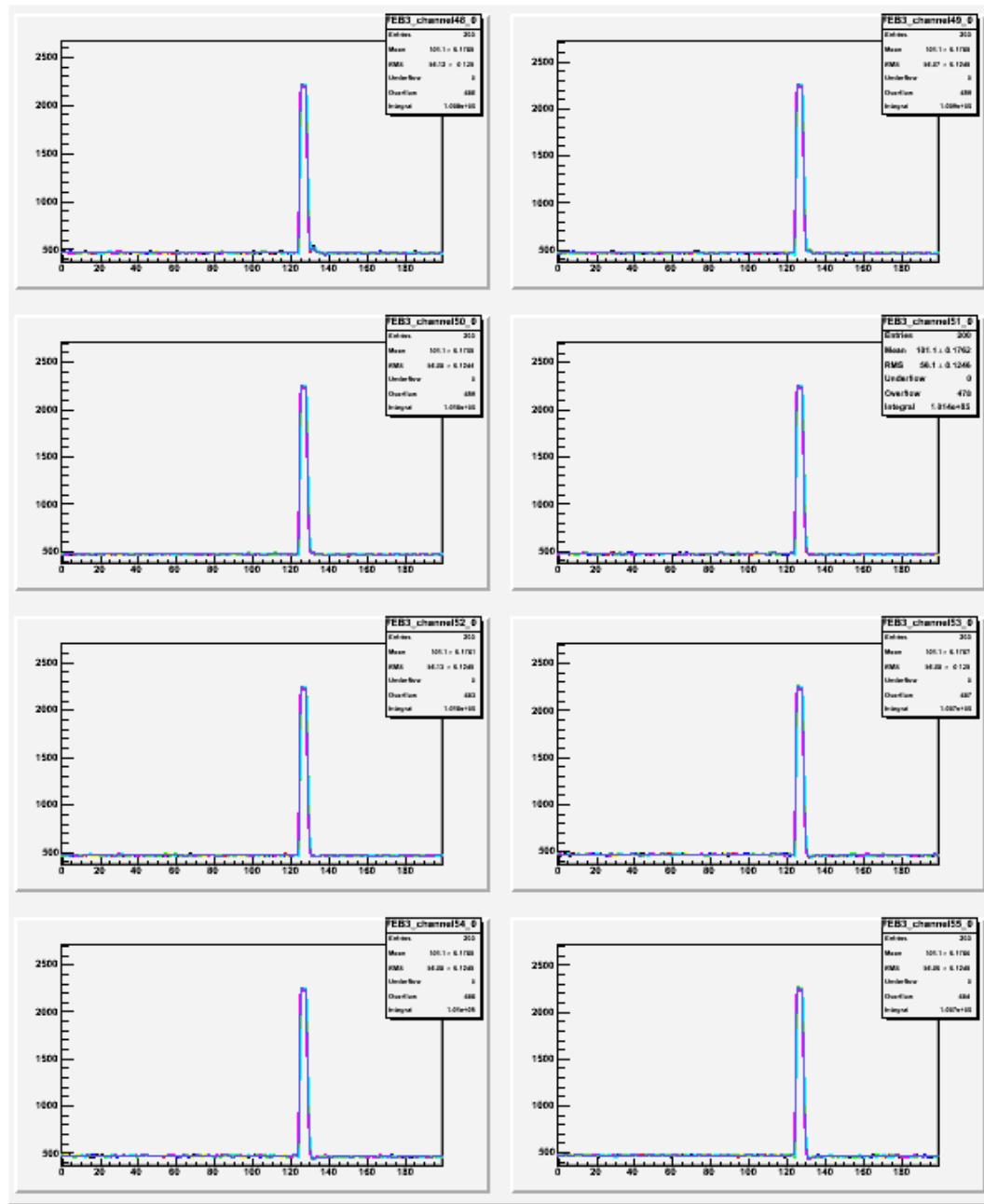
Test Stand Received!

- Arrived yesterday with Chen et al from BNL, along with 146 receiver ADC boards.
- Installed and working in 1-2 hours.
- Everything seems to be working fine
 - New code from Chen to configure AFG fixes frequency issue (no longer manual adjust)
 - PCIe card controlling routines from Georgia
 - ROOT calibration analysis macros from Georgia

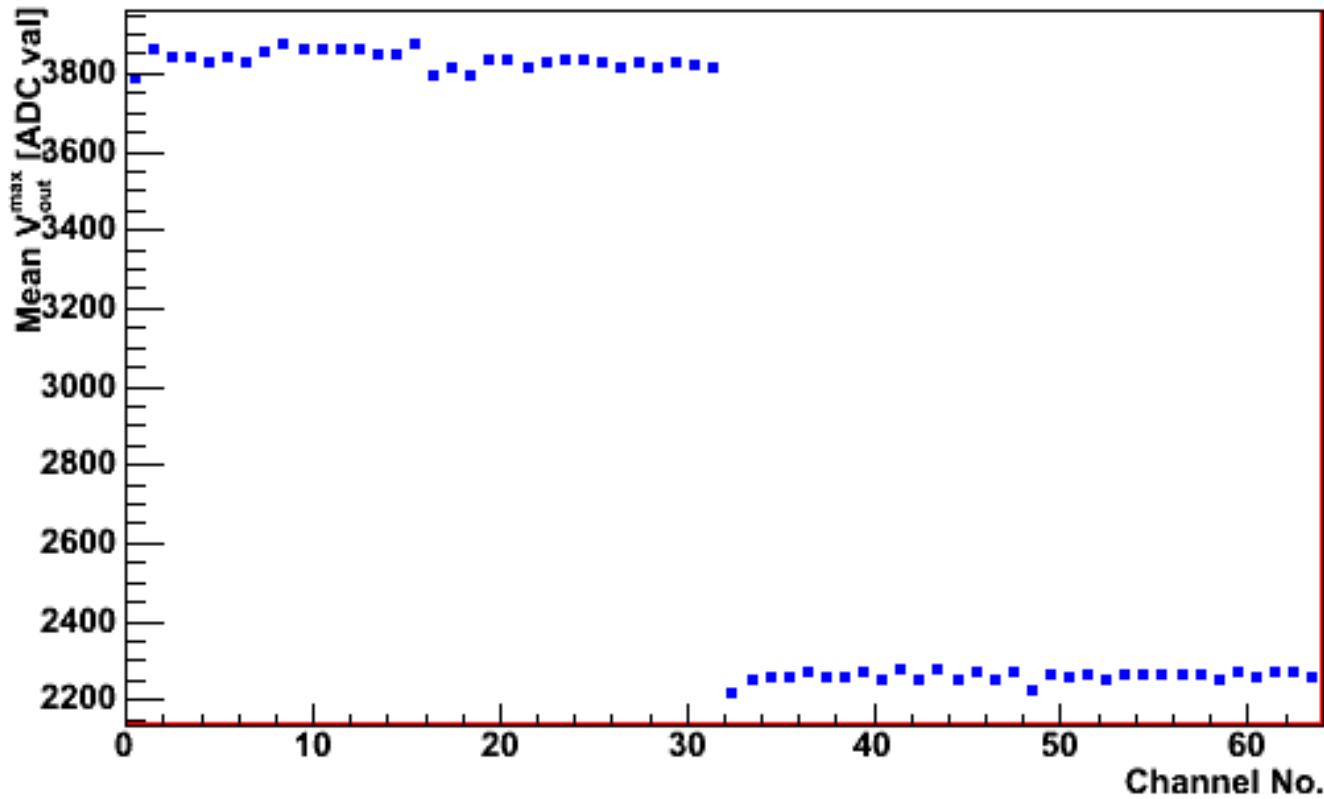








Eight random channels from
an FEM displaying ten events
generated with the pulser.
X-axis: ADC ticks
Y-axis: ADC



Mean max ADC value read out from each channel in an option-1 FEM for ten pulser events.

What's the Plan

- Assemble Nevis' FEM boards with BNL's ADC boards.
- Document serial numbers of mated FEM+ADC boards for database.
- Use the test stand to run baseline tests and calibration pulse tests, including linearity.
 - Goal: functionality and FEM+ADC connections.
 - Running three FEM+ADC boards at a time.
 - Reading out through crate controller.